# Depth Correction for Time-of-Flight Camera Using Depth Distortion Dependency on Pulse Width of Irradiated Light

28th IEEE International Conference on Image Processing(ICIP2021) 2021.9.19-22

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## Background

- •Time-of-Flight (ToF) Camera
  - A kind of 3D camera that estimates depth based on round-trip time of light
  - Low cost, high speed, and compact form due to simple measurement system
- •Drawback: Depth Distortion
  - A kind of depth error depending on material of object
  - Mainly caused by optical phenomenon (reflection, scattering, transmission, etc.)



Difficult to model depth distortion process, so machine learning approach is commonly used for depth correction

#### **Conventional Depth Correction Method(1):** [Fuersattel+,2017]



This method may not work well for diverse materials

## **Conventional Depth Correction Method(2):** [Tanaka+,2017]

#### Method

- •Measure multiple depths (not 1-shot) containing material property using multiple frequencies & positions
- Estimate material, then get depth error from LUT using material as query Limitation
- •Require sweeping (camera and object are fixed in many industrial applications)
- •Performace may degrade for unknown materials (LUT includes **only known materials**)



**Proposed method can overcome these limitation because of:** 

- 1) no sweeping in feature extraction
- 2) direct estimation w/o material classification

#### **Proposed Method: Feature Extraction**

# Utilize property that depth changes with pulse width of irradiation light and material

- ✓ Measure multiple depths using multiple pulse width with fixing Gate1,2 (unusual setting)
- ✓ No sweeping unlike conventional method
- ✓ We confirmed proposed **feature vector depends on material** by formula and simulation

Measurement procedure

Results of multiple measurements





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#### **Proposed Method: Depth Correction**

#### Estimate depth error based on feature vector using neural network

 Direct manner may deal with unknown material\* by utilizing similarity of intermediate features \*Not exactly same but similar materials in training data



### **Experimental Setup**

#### •ToF camera

- Model: In-house prototype using Panasonic's ToF sensor (MN34902BL)
- Pulse widths: 30,32,...,44ns (8 pattern)
- # of frames: 300
- Calibrate measured value[a.u.] into measured depth[cm] based on depth of reference object
- •Object for training data
  - Material: 10 cardboards, 4 plastic boards, 8 plastic cardboards
  - Fixed parallel to sensor surface using photo frame-like jig
  - Distance from ToF camera : 85,90,..., 140cm (12 pattern)



### **Evaluation for Known Materials**

- •Same material for training and testing
- •Randomly selected 80% of pixels for training, remaining 20% for testing
- •Calculate MAE of each object, then evaluate mean(MAE<sub>mean</sub>) and max(MAE<sub>max</sub>) for each material

Method	MAE <sub>mean</sub> / MAE <sub>max</sub> [cm]				
	Cardboard	Plastic	Plastic cardboard	All	
w/o correction	3.05 / 3.69	6.57 / 9.86	5.25 / 6.83	4.25 / 9.86	
[Fuersattel+,2017]	0.55 / 1.60	1.59 / 1.96	0.54 / 0.98	0.73 / 1.96	
[Fuersattel+,2017]*	0.71 / 1.37	0.96 / 1.63	0.61 / 1.24	0.70 / 1.63	
Ours	0.43 / 0.55	0.94 / 1.19	0.72 / 1.04	0.64 / 1.19	

\*)Using MLP instead of Random Forest

**Proposed method outperform conventional method** 

## **Evaluation for Unknown Materials (1)**

•These two object are not exactly same materials in training data, but similar to plastic or cardboard



Proposed method work well for slightly different materials from trainging data

## **Evaluation for Unknown Materials (2)**

•Evaluate unknown materials by changing combination of materials in training data

Schematic image of evaluation scenario



Material in training data		MAE <sub>mean</sub> on testing material [cm]			
Cardboard	Plastic	Plastic Cardboard	Cardboard	Plastic	Plastic cardboard
$\checkmark$			0.24	4.01 🥆	2.38
$\checkmark$	$\checkmark$		0.33	0.82	2.28
$\checkmark$		$\checkmark$	0.33	2.93	0.69
			Better MAE desipite <b>unknown material</b>		

Proposed method work well for unknown materials by interpolating from known material information in the feature space

#### Summary

### ♦Our method

- Feature extraction without sweeping
- Direct depth correction without material classification

#### Experimental Results

•Our method can deal with **unknown materials** 

#### Future work

- •Expand target materials
- •Reduce variation in MAE between materials



# Thank you

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